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# Exploring Extreme Environments with Adequate Temporal Resolution

SAND2019-4654C  
nuclear science  
User Facilities

K. Hattar

Sandia National Laboratories

April 26<sup>th</sup>, 2019



## Collaborators:

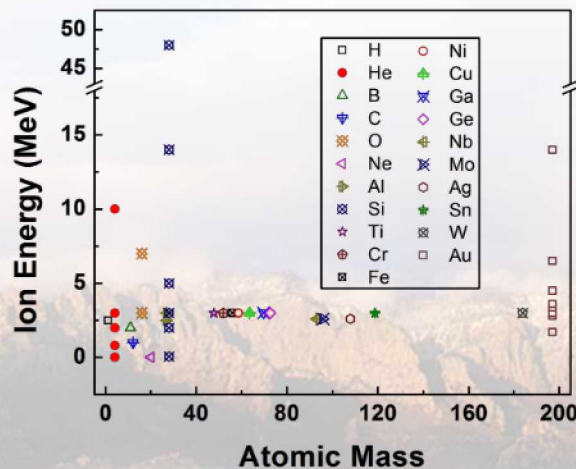
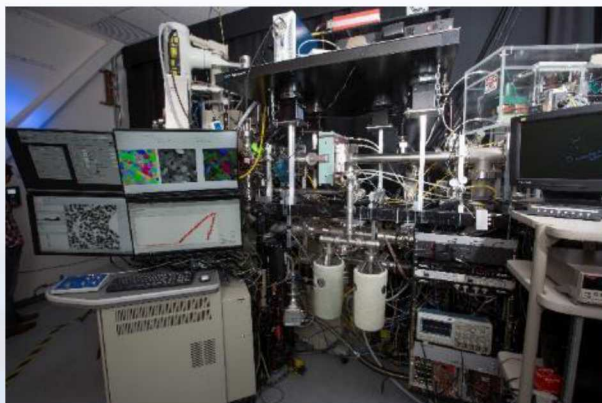
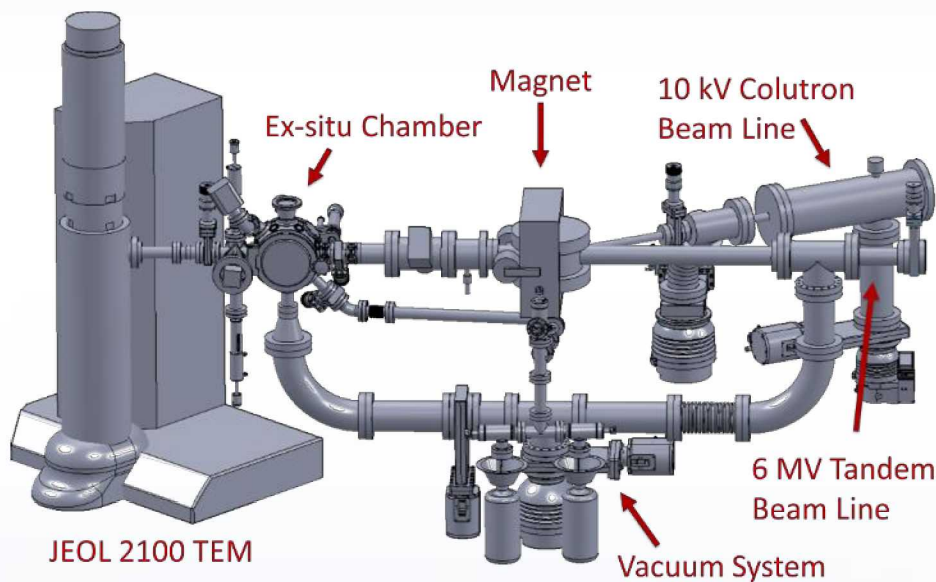
- D.L. Buller, D.C. Bufford, S.H. Pratt, T.J. Boyle, B.A. Hernandez-Sanchez, S.J. Blair, B. Muntifering, C. Chisholm, P. Hosemann, A. Minor, J. A. Hinks, F. Hibberd, A. Ilinov, D. C. Bufford, F. Djurabekova, G. Greaves, A. Kuronen, S. E. Donnelly, K. Nordlund, F. Abdeljawad, S.M. Foiles, J. Qu, C. Taylor, J. Sugar, P. Price, C.M. Barr, D. Adams, M. Abere, L. Treadwell, A. Cook, A. Monterrosa, IDES Inc, J. Sharon, B. L. Boyce, C. Chisholm, H. Bei, E.P. George, W. Mook, Hysitron Inc., G.S. Jawaharram, S. Dillon, R.S. Averbach, N. Heckman, J. Carroll, S. Briggs, E. Carnes, J. Brinker, D. Sasaki, T. Nenoff, B.G. Clark, P.J. Cappillino, B.W. Jacobs, M.A. Hekmaty, D.B. Robinson, L.R. Parent, I. Arslan, & Protochips, Inc.

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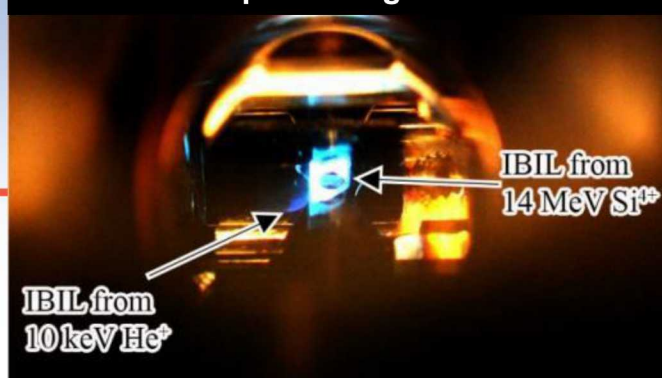
# Sandia's Concurrent *In situ* Ion Irradiation TEM Facility

Collaborator: D.L. Buller

10 kV Colutron - 200 kV TEM - 6 MV Tandem



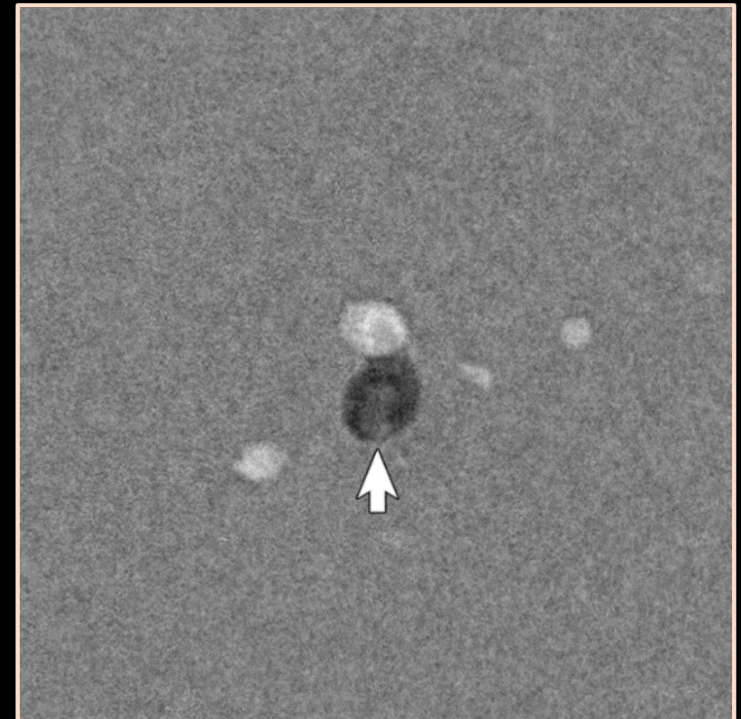
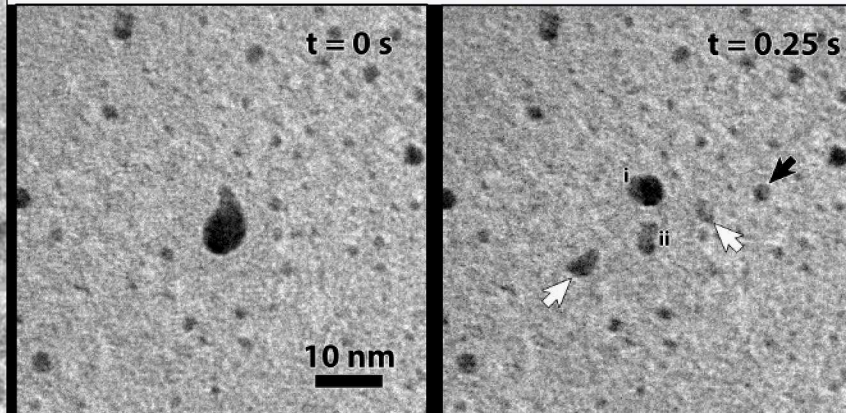
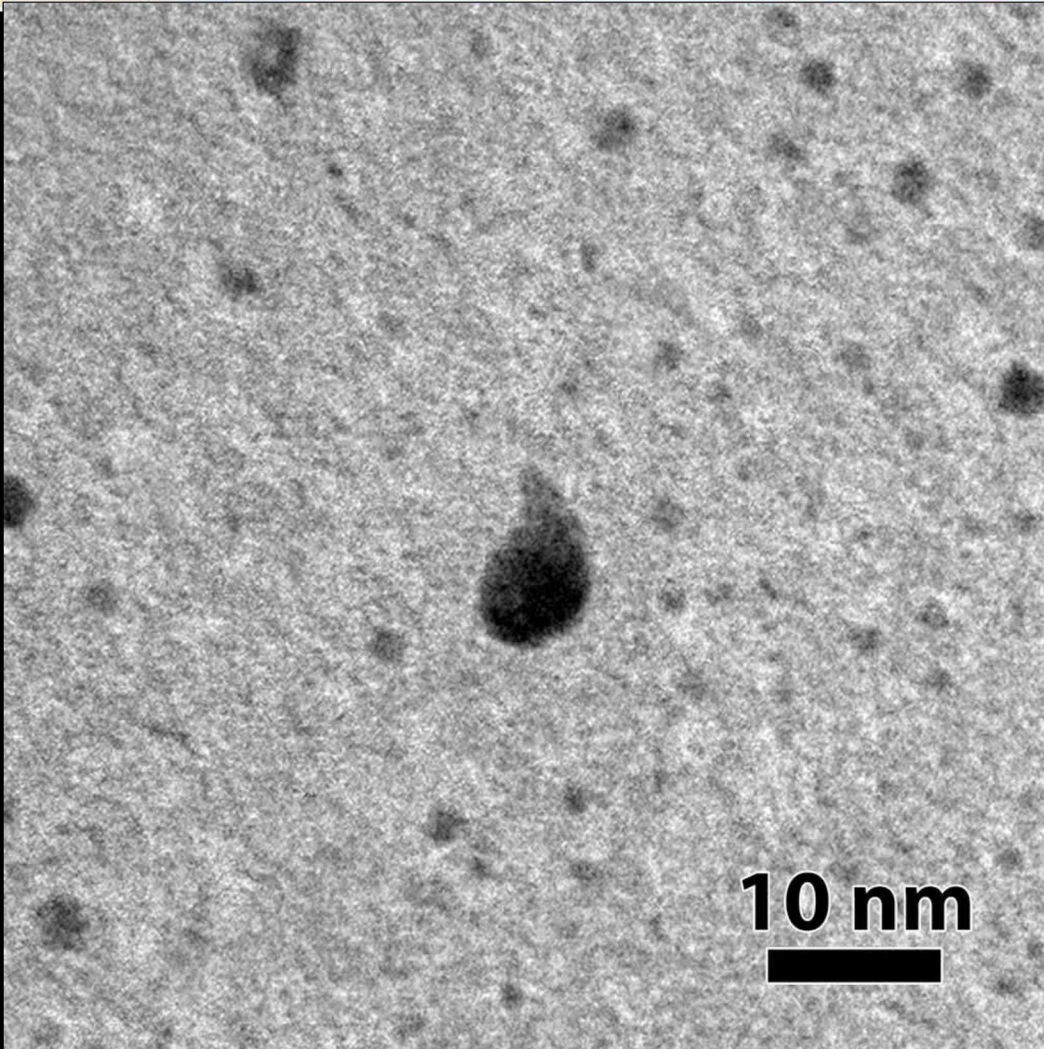
IBIL from a quartz stage inside the TEM





# Single Ion Strikes: 46 keV $\text{Au}^{1+}$ ions into 5 nm Au nanoparticles

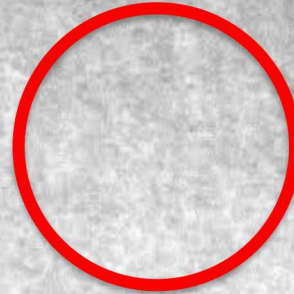
Collaborator: D.C. Bufford





# Motivation: In-Situ Single Ion Strikes in Si

**30 nm**



difference  
image

- 1.7 MeV Au into single crystal Si
- Single ion strikes can be observed in semiconductors
- Non-symmetric structure in contrast to the spherical approximation

**Can we go beyond this to observe:**

- Important aspects of structural evolution (ns to hrs.)?
- Evolution in more complex systems (GaAs)?
- Directly correlate it to key model parameters?



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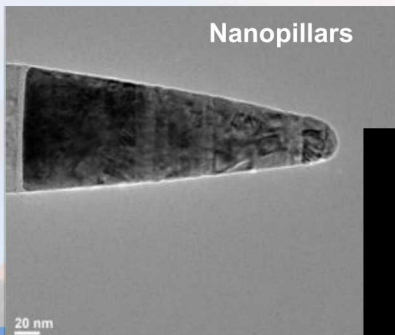
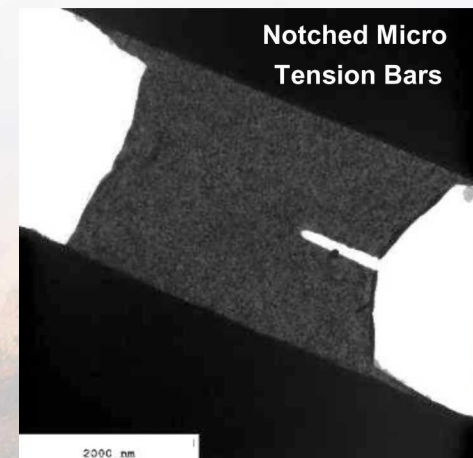
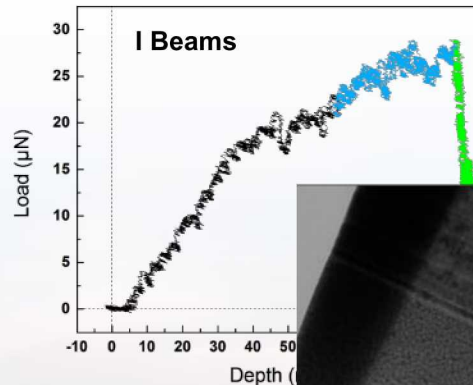
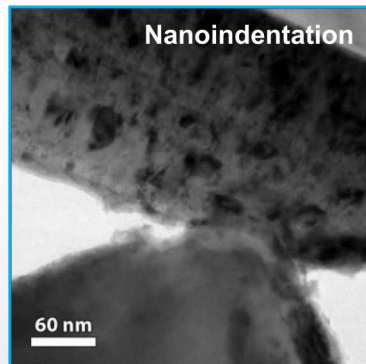
# *In situ* Quantitative Mechanical Testing

Contributors: J. Sharon, B. L. Boyce, C. Chisholm, H. Bei, E.P. George, P. Hosemann, A.M. Minor, & Hysitron Inc.



Hysitron PI95 *In Situ* Nanoindentation TEM Holder

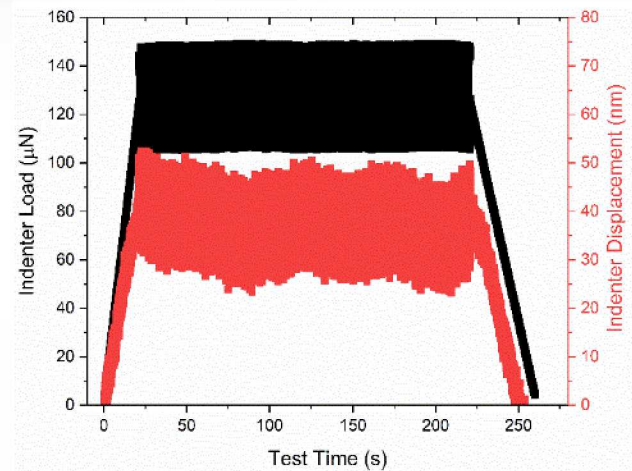
- Sub nanometer displacement resolution
- Quantitative force information with  $\mu\text{N}$  resolution
- **Concurrent real-time imaging by TEM**





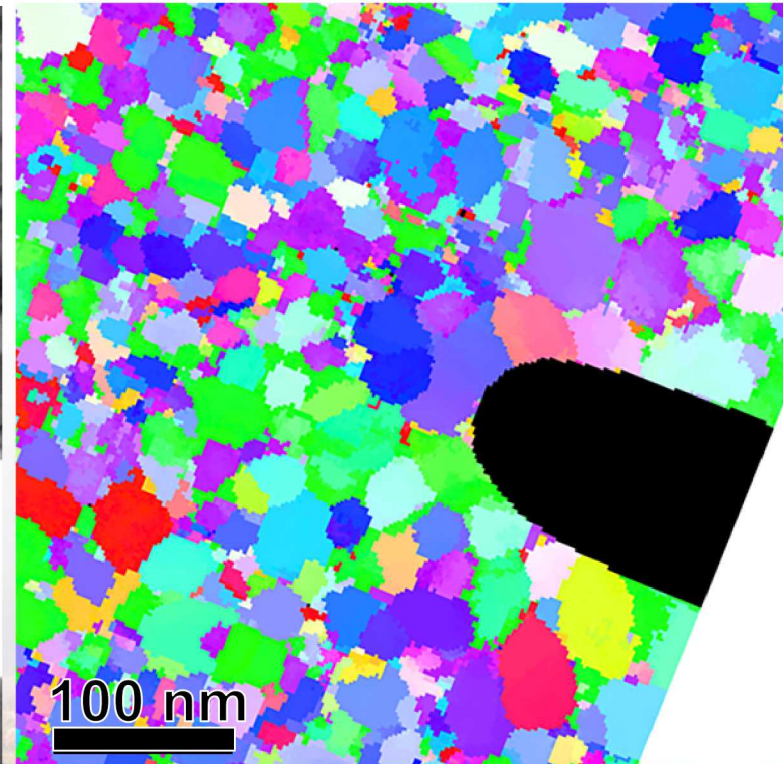
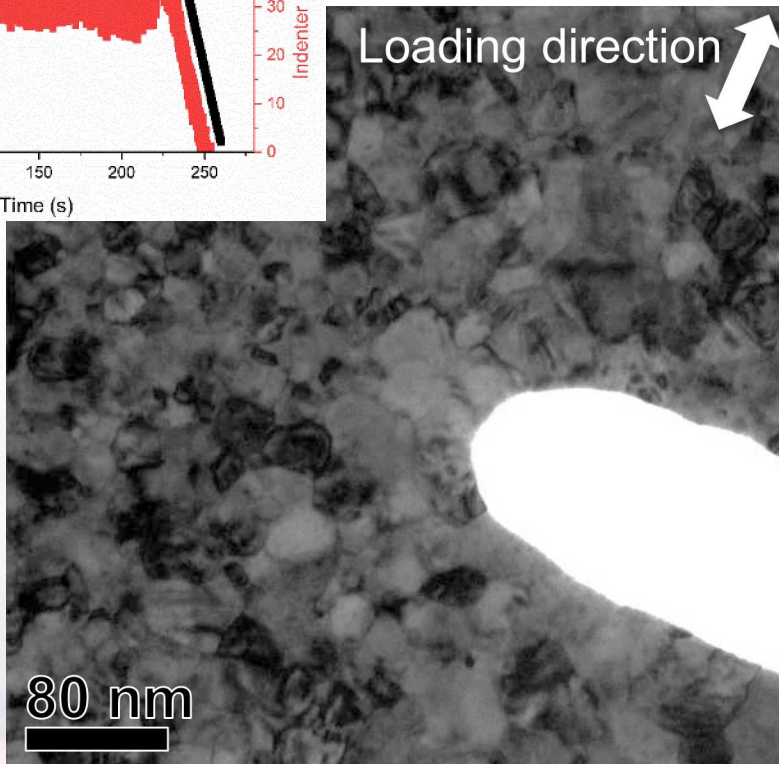
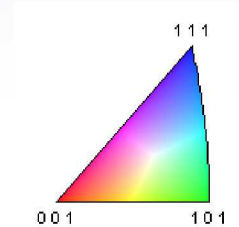
# Cyclic Loading Coupled with ACOM

Collaborators: C. Barr & W. Mook



Mean load ( $P_{\text{mean}}$ ) = 135  $\mu\text{N}$

Amplitude load ( $P_{\text{amp}}$ ) = 35  $\mu\text{N}$

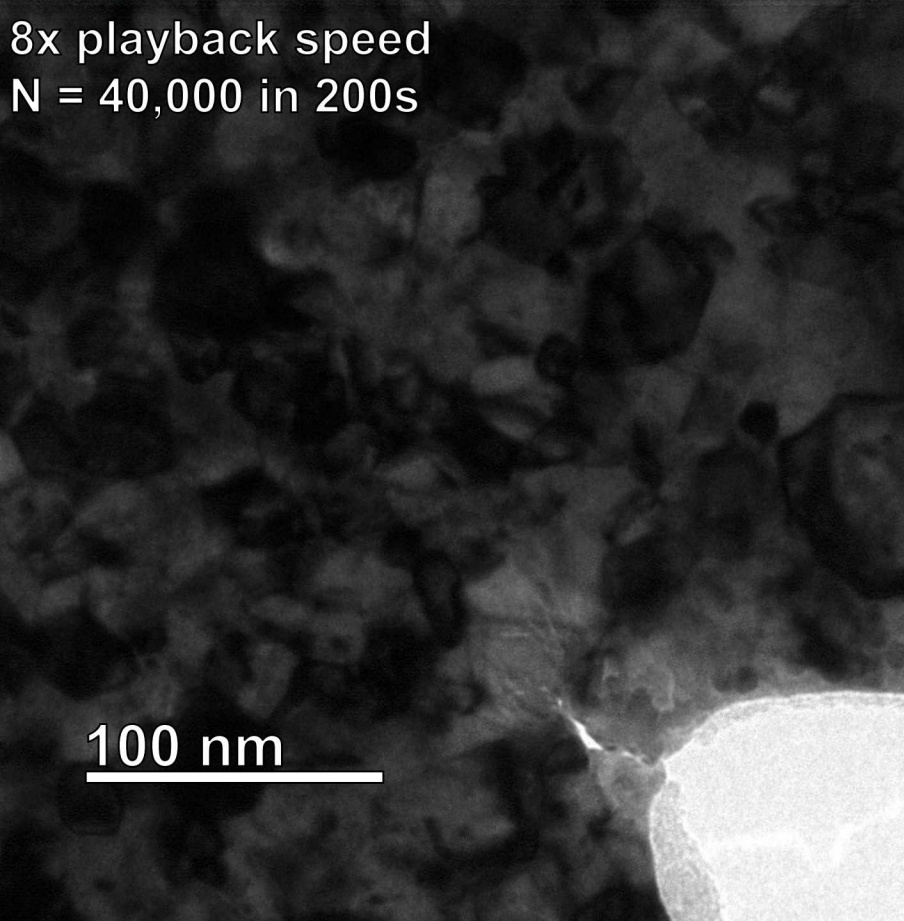


Orientation maps pre-, intermediate, and post- in-situ mechanical test can assist in deconvoluting possible mechanisms during cyclic loading

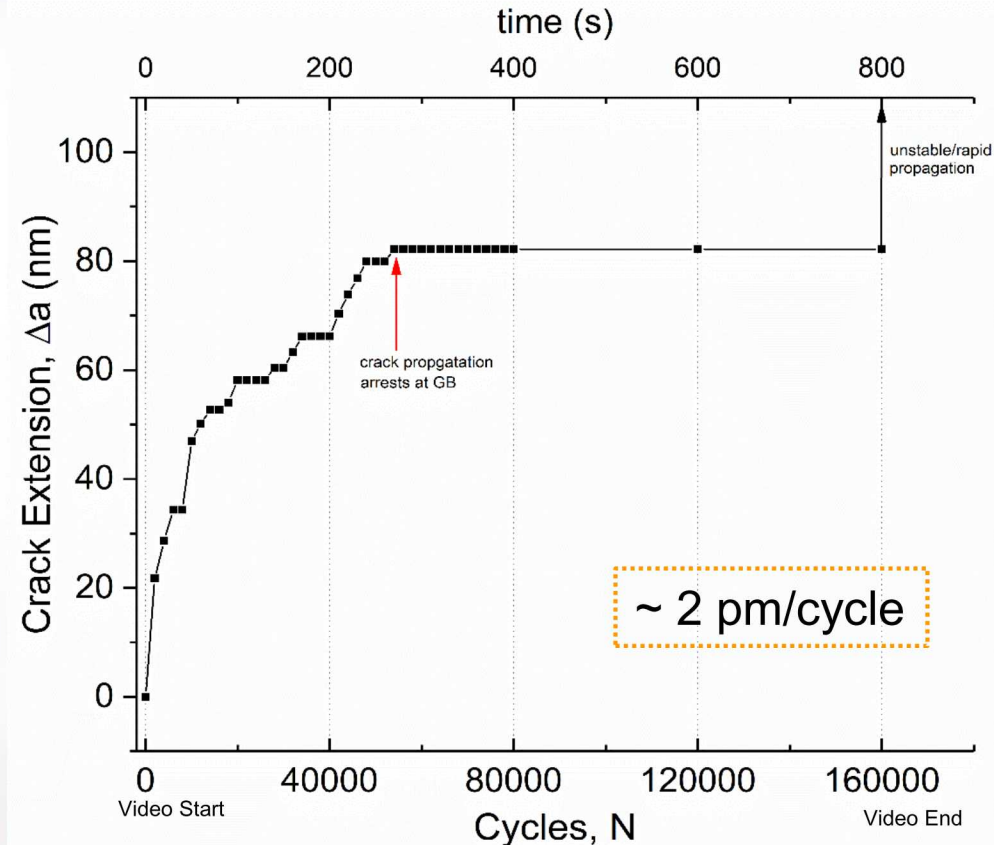


# Cyclic Loading: Complex Crack Propagation

Collaborators: C. Barr & W. Mook



- Mean load: 135  $\mu\text{N}$ ; Amplitude load: 35  $\mu\text{N}$
- 200 Hz, 200s test (15 fps 1k x 1k camera)



- $da/dN = 1.7 \times 10^{12} \text{ m/cycle}$
- Non-linear crack extension rate
- Crack propagation path changes “direction”



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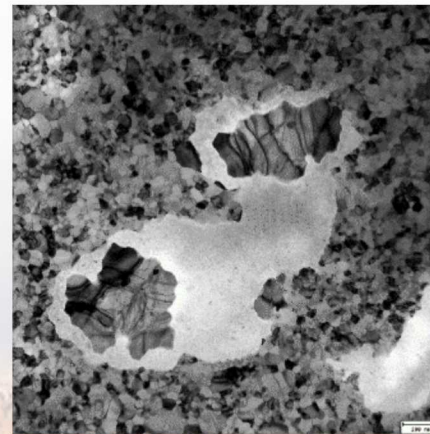
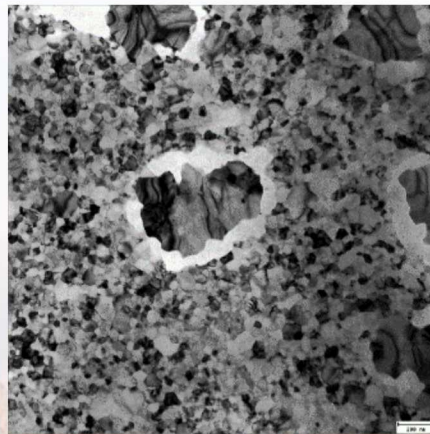
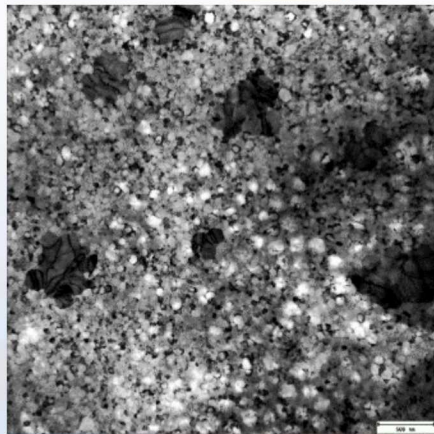
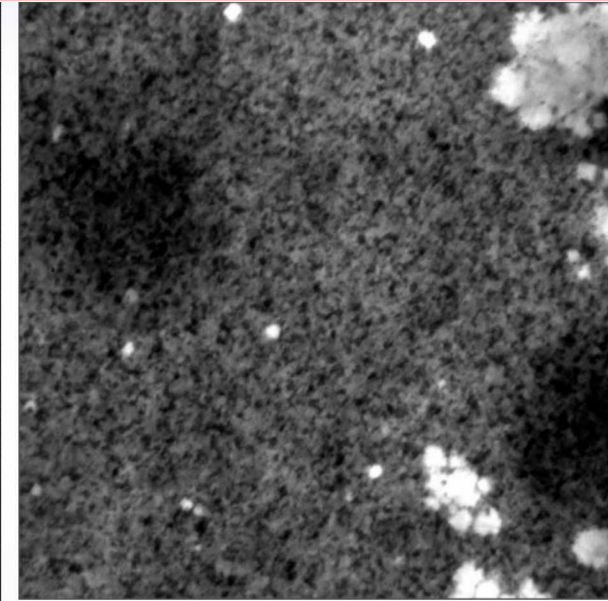
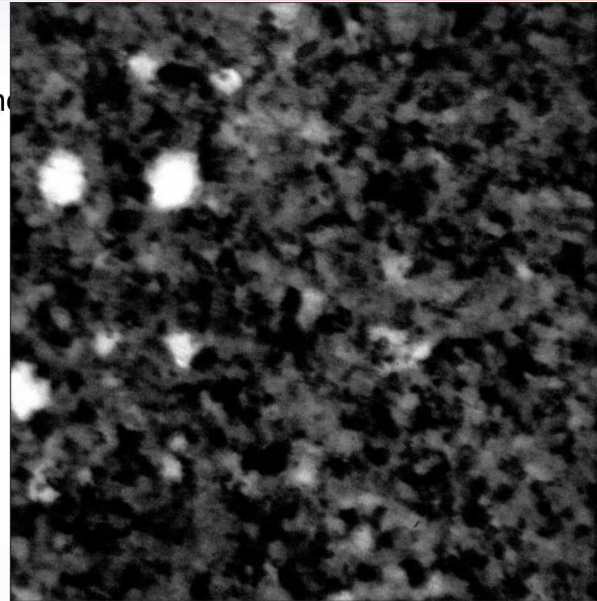
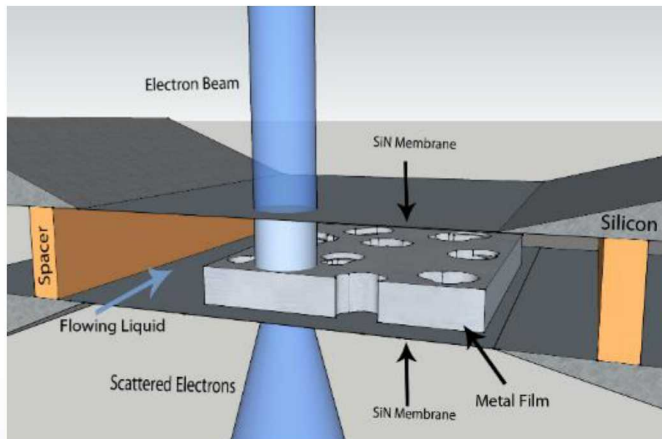


# Can We Gain Insight into the Corrosion Process through *In situ* TEM?

Contributors: D. Gross, J. Kacher, I.M. Robertson & Protochips, Inc.

## Microfluidic Stage

- Mixing of two or more channels
- Continuous observation of the reaction channels



Pitting mechanisms during dilute flow of acetic acid over 99.95% nc-PLD Fe involves many grains. Large grains resulting from annealing appear more corrosion tolerant

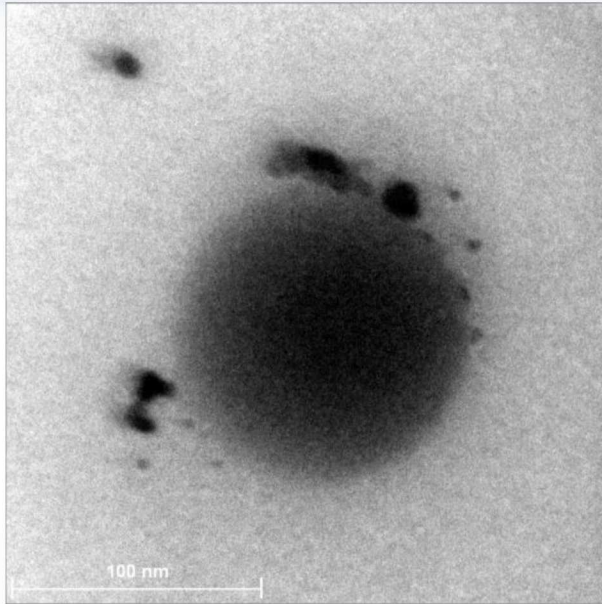


# Other Fun Uses of Microfluidic Cell

## Protocell Drug Delivery

S. Hoppe,  
E. Carnes,  
J. Brinker

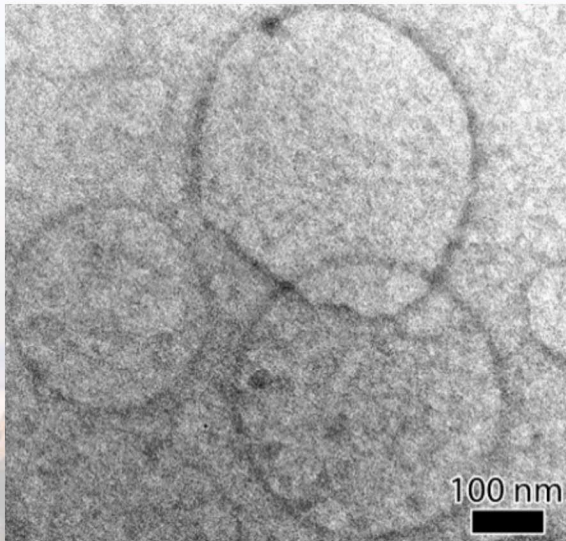
Liposome  
encapsulated  
Silica destroyed  
by the electron  
beam



## Liposomes in Water

S. Hoppe,  
D. Sasaki

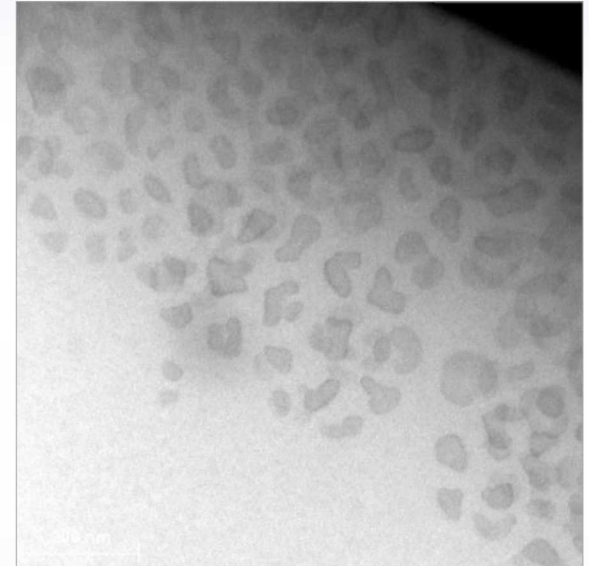
Liposomes  
imaged in  
flowing aqueous  
channel



## BSA Crystallization

S. Hoppe

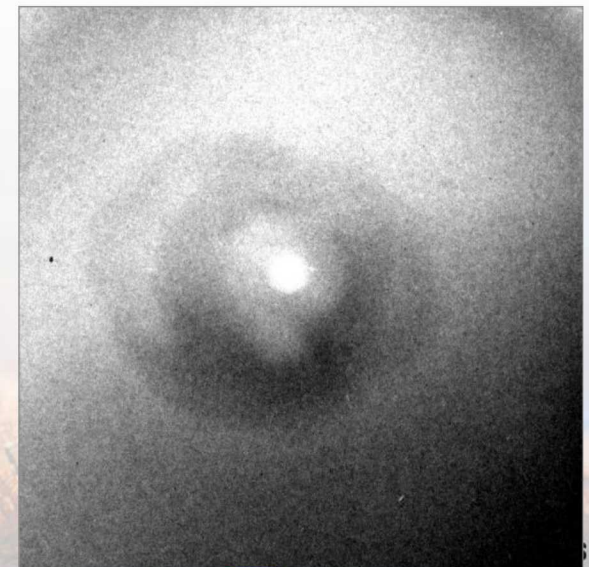
Crystallization of excess  
Bovine Serum Albumen  
during flow



## La Structure Formation

S. Hoppe,  
T. Nenoff

La  
Nanostructure  
form from  $\text{LaCl}_3$   
 $\text{H}_2\text{O}$  in wet cell  
due to beam  
effects

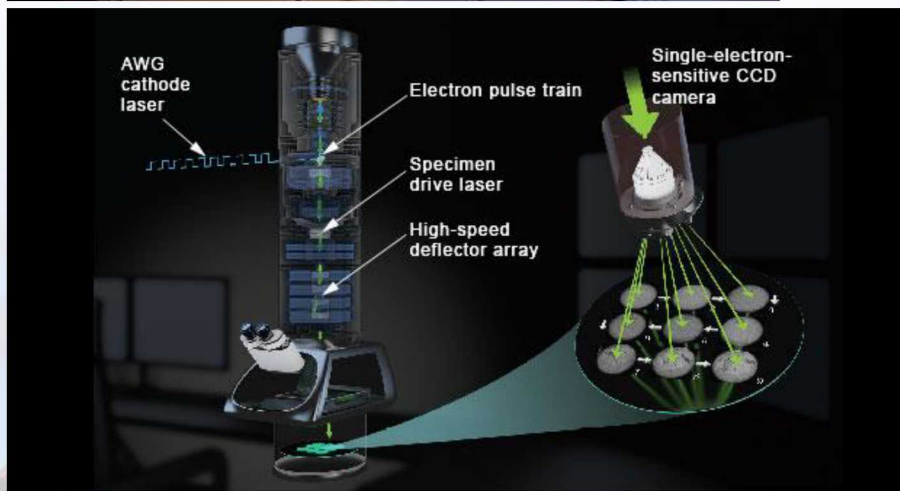


# Can I<sup>3</sup>TEM and DTEM systems be combined?

LLNL DTEM



SNL I<sup>3</sup>TEM



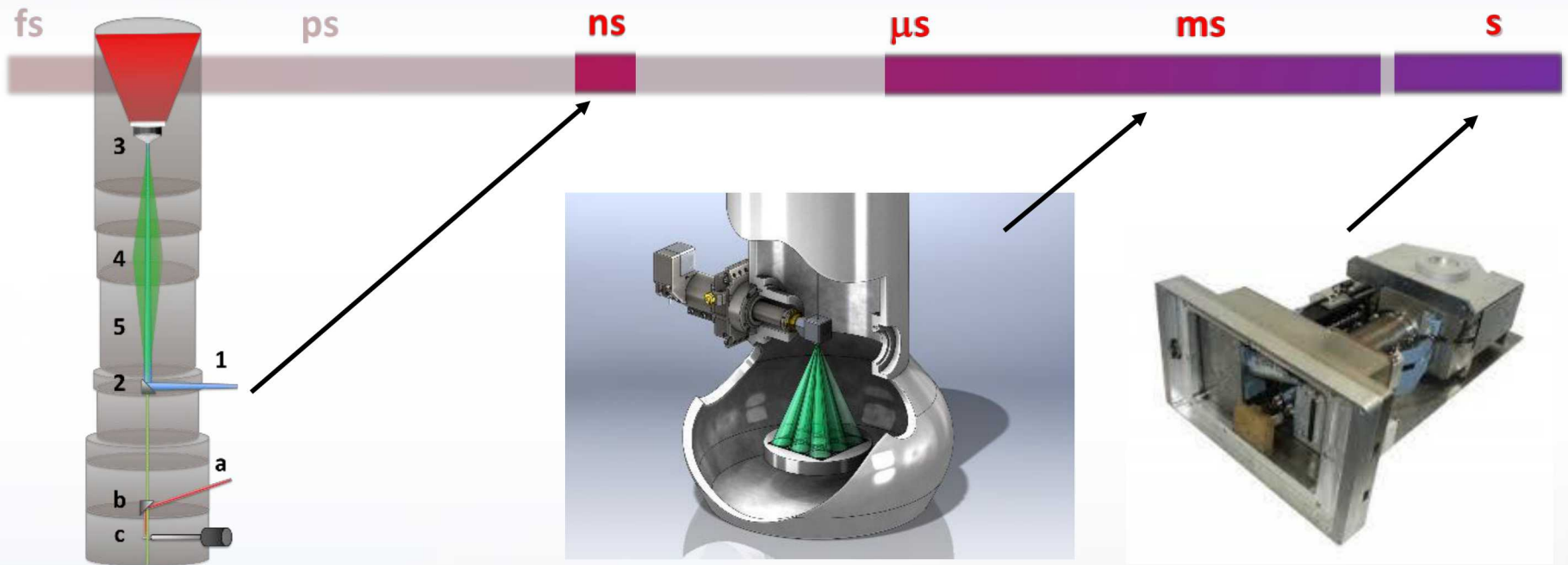
## Goal:

Combine the state-of-the-art in microscopy of DTEM and I<sup>3</sup>TEM to elucidate the response of extreme overlapping environments with adequate spatial and temporal resolution.





# Increasing Temporal Resolution



## ■ DTEM

- Laser induced photoemission of electrons is needed to achieve sufficient current density to produce an image
- Provides nanosecond imaging of irreversible process

## ■ Deflector System

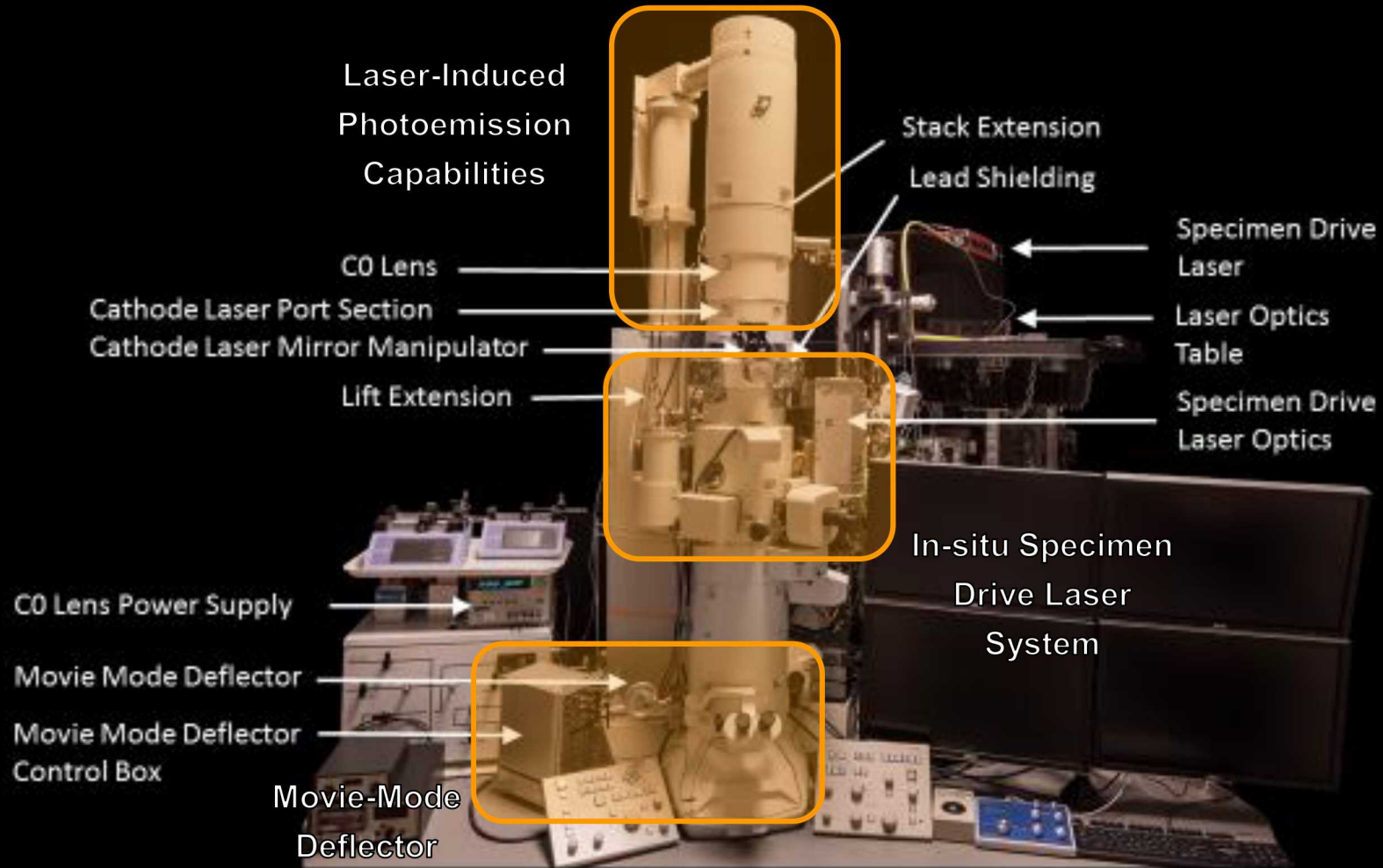
- Multiple images acquired on single frame
- Microsecond imaging possible
- Virtually no missing data (nanosecond gaps)

## ■ Standard 1K TVIPS camera

- Due to camera read out rate few images can be acquired
- 10-20fps maximum
- Missing data during camera readout



# Current Status of Laser Addition and DTEM Conversion

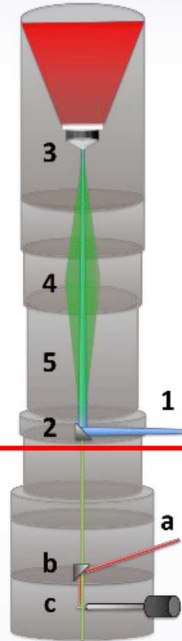




# In-situ Specimen Drive Laser System

## Specimen Drive Laser

- a. Adjustable power 1064 nm infrared specimen (IR) drive laser
- b. IR laser is reflected directly onto the specimen with metal mirror
- c. Heat specimens in *in situ* holders, which otherwise would not be possible
- Laser capabilities:
  - 2-20 Watts
  - Pulsed or continuous operation
  - 50  $\mu\text{m}$  diameter spot size
  - Positioning mirror, which can be used during laser operation



## Electron Beam

## IR Laser

## Laser Alignment TEM Holder

- Phosphor screen
- Borescope
- CCD camera
- Precise alignment of the laser to the electron beam

# Initial Laser Heating Observations

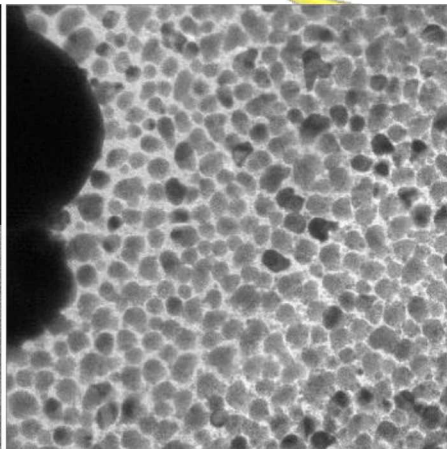
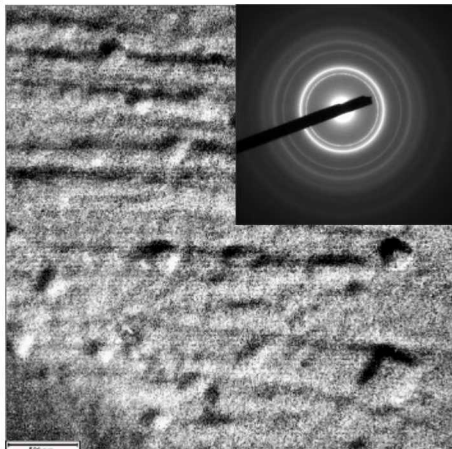
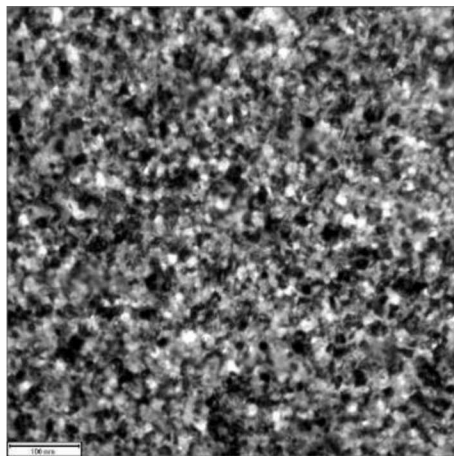
Collaborator: P. Price, C.M. Barr, D. Adams, M. Abere

Pt Grain Growth

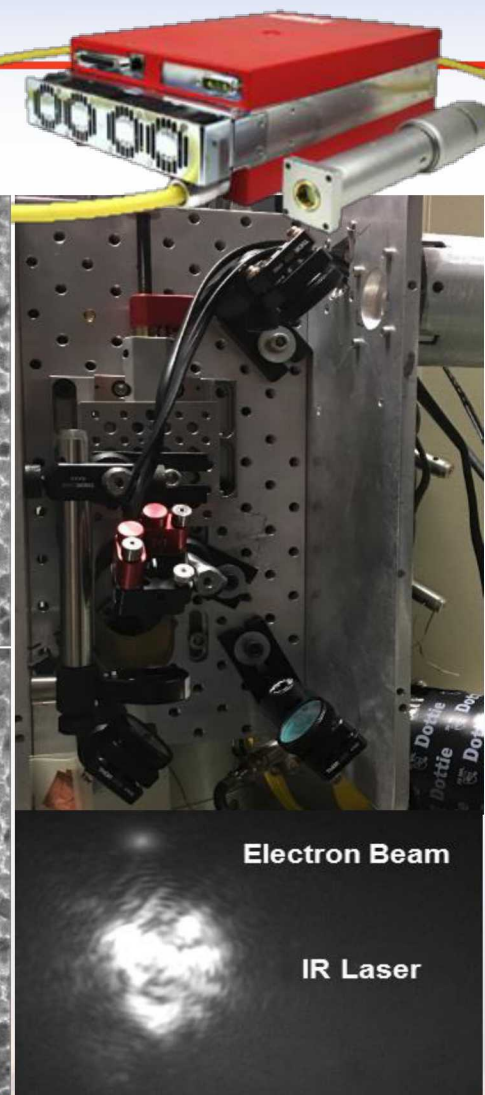
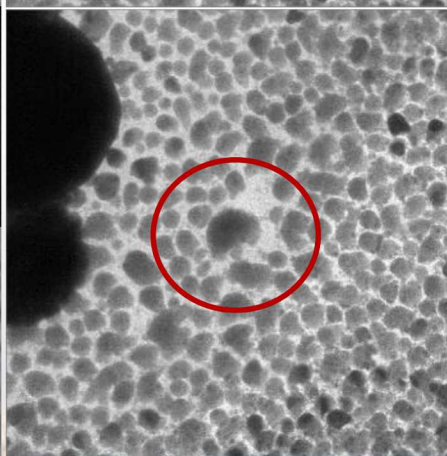
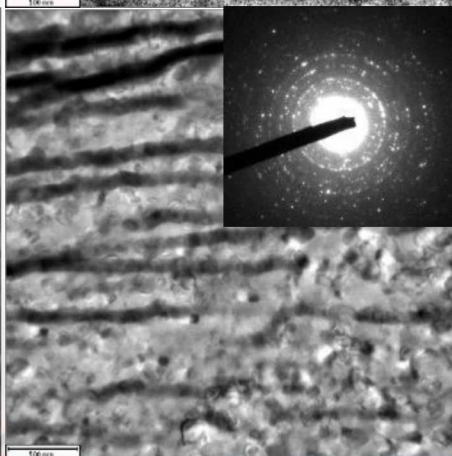
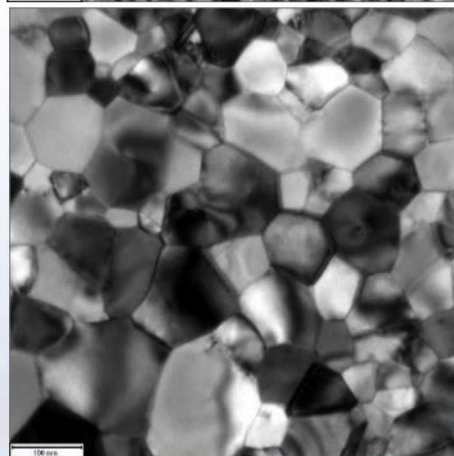
Reactive Multilayer Films

Nanoparticle Sintering

Before



After



We can now introduce rapid thermal heating with  
any TEM stage or ion beam conditions

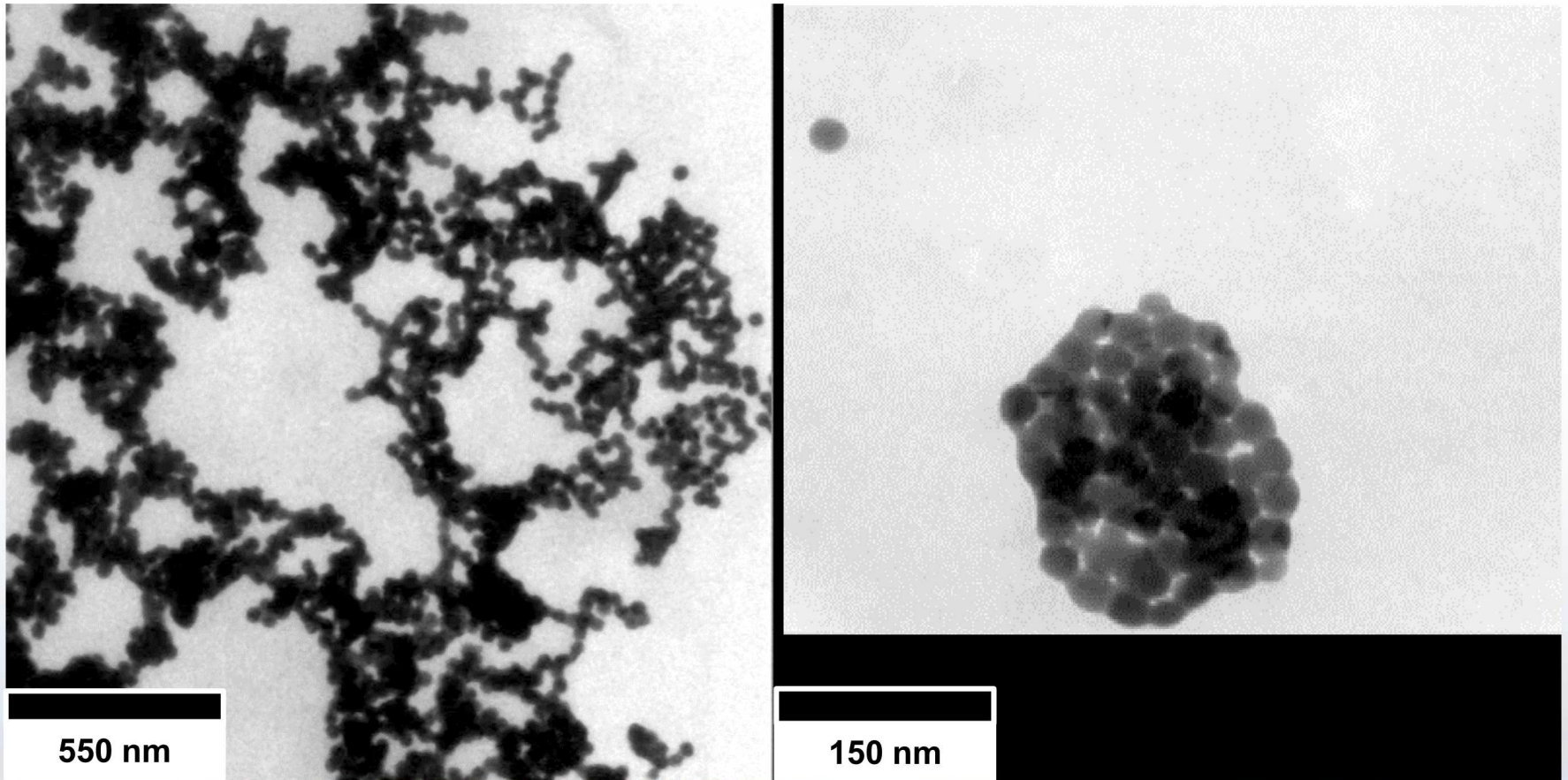


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# Complex Interaction Au NPs Exposed to Laser Irradiation

Contributors: P. Price, L. Treadwell, A. Cook



Speed = 2.5x



**A Complex Combination of Sintering, Reactions, and Ablation Occurs**

# $\mu$ s Resolution with a Standard Camera

Collaborator: P. Price, A. Monterrosa, D. Adams, M. Abere, & IDES Inc.

fs

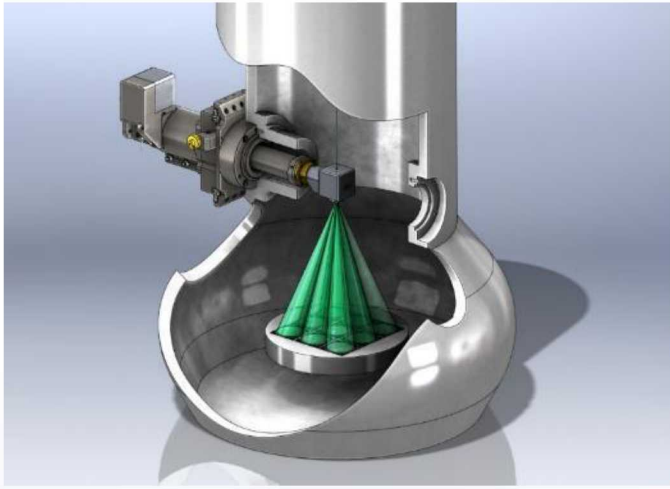
ps

ns

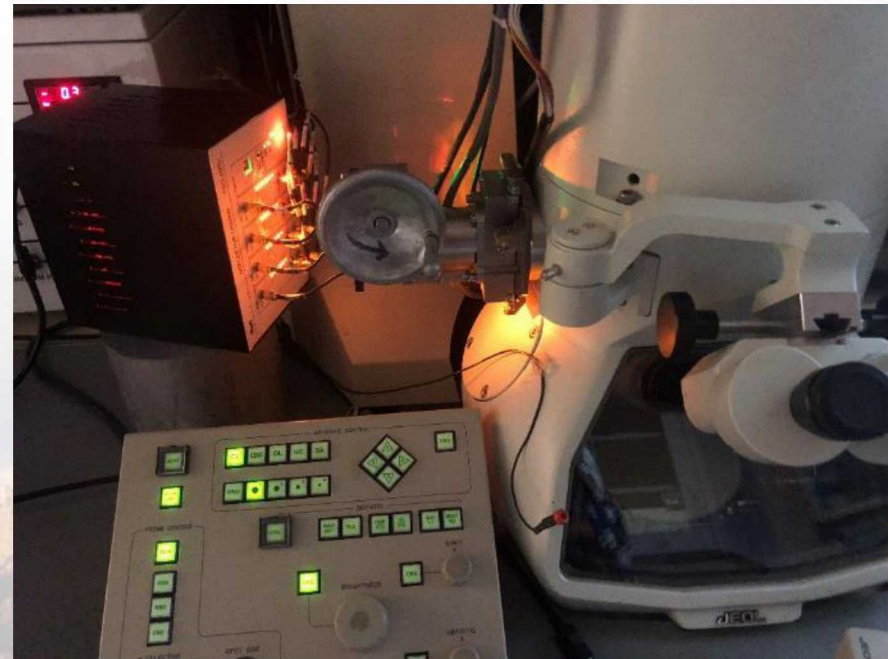
$\mu$ s

ms

s

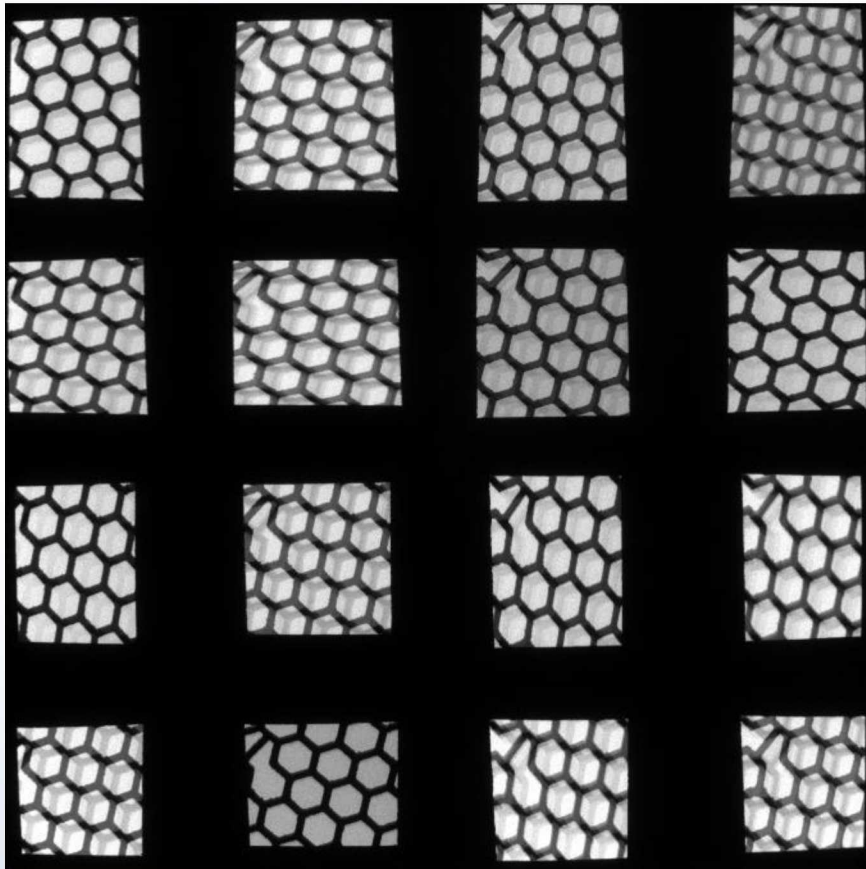


- Electrostatic deflection of electrons
- 4, 9, or 16 images per frame, spread over a large camera
- Any exposure time up to the limits of the camera
  - Ultimate limit is beam current/brightness

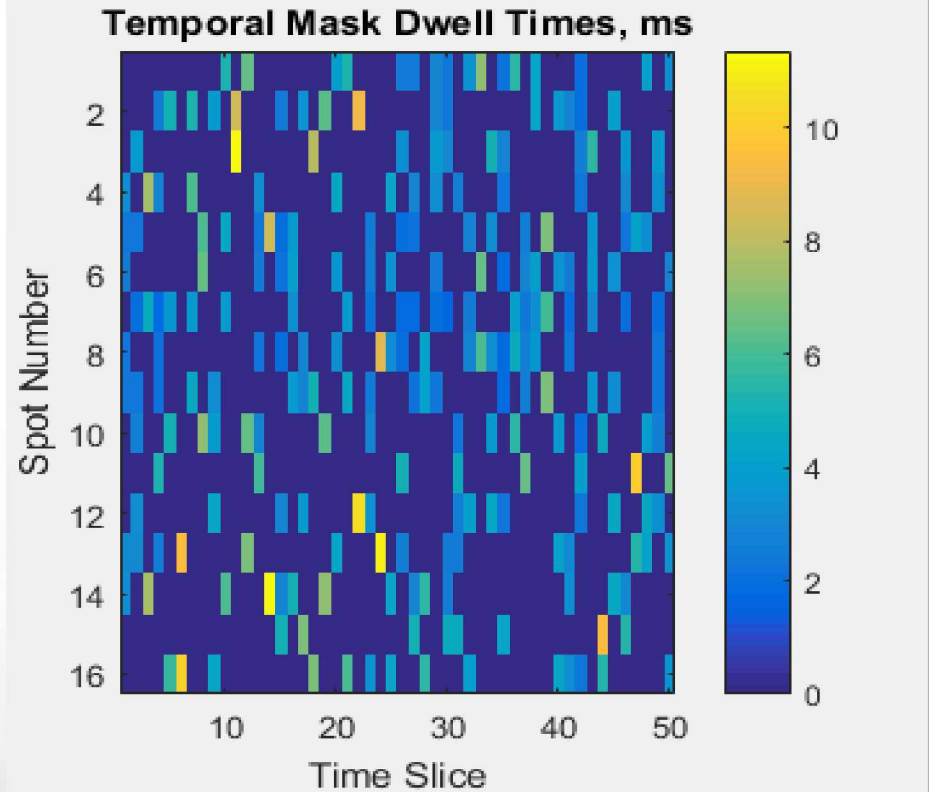




# Movie Mode & Temporal Compressive Sensing



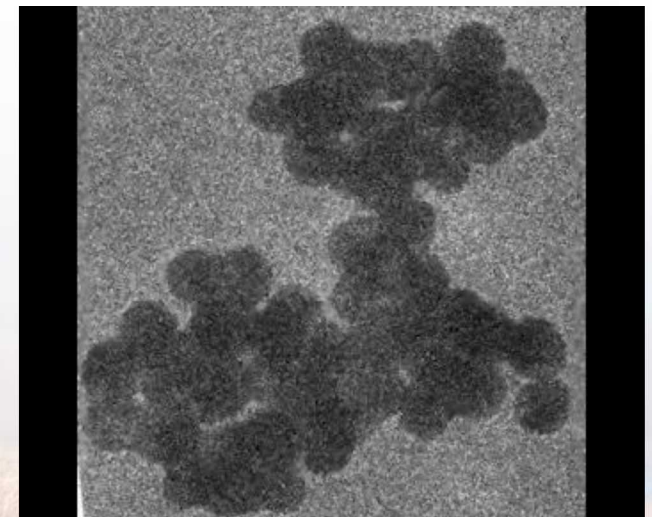
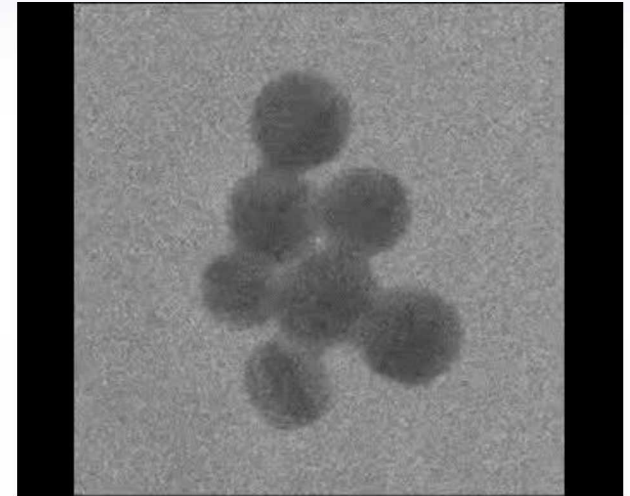
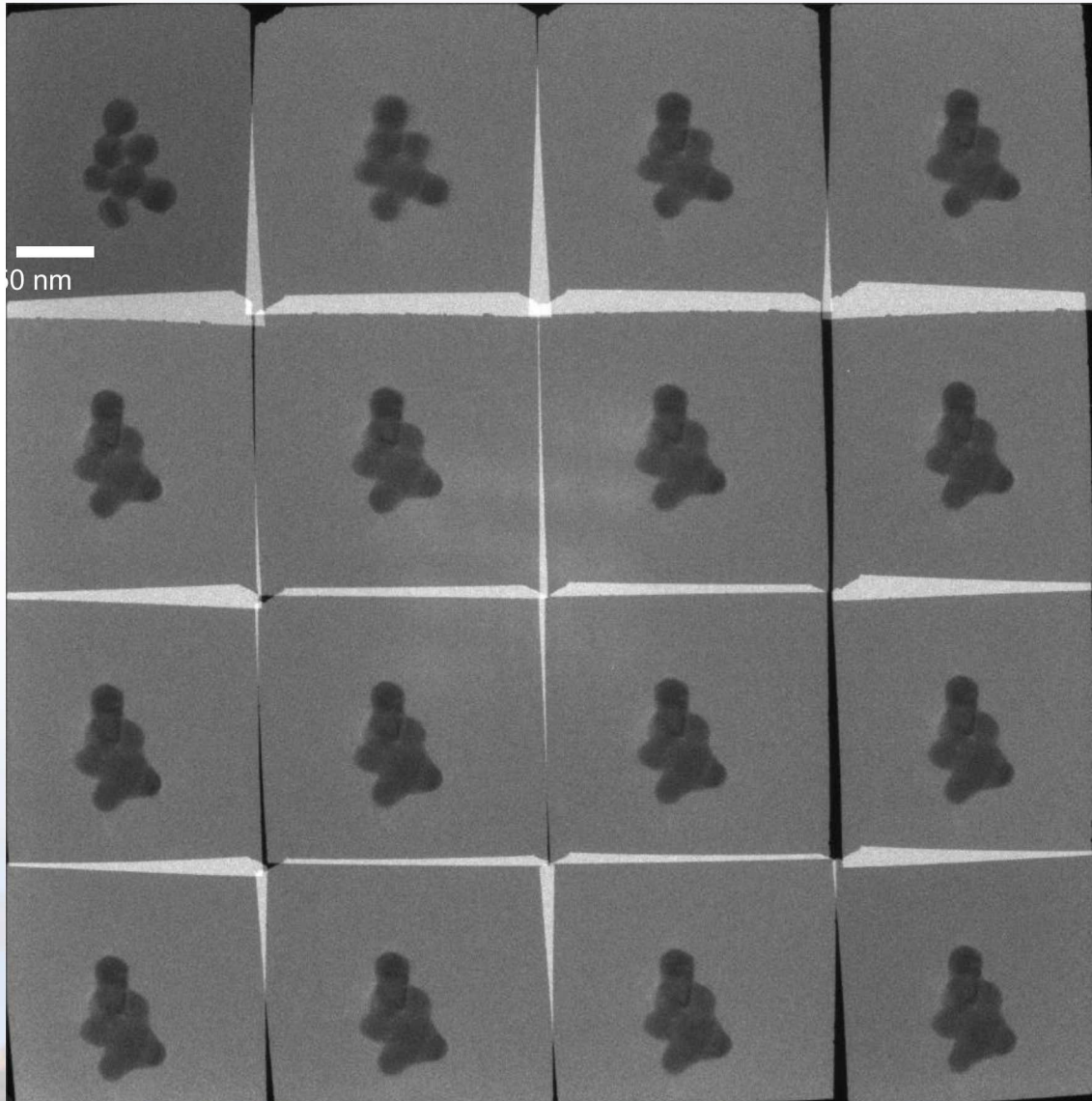
Up to 100 exposures can be acquired on a single camera frame giving  $\mu\text{s}$  temporal resolution



- Electron intensity of a single exposure is randomly distributed to multiple images within a single frame
- Record of random mask used to distribute exposure intensity is later used deconvolute images

# 1-to-1 Frame Capture (<5 ms per frame) Sintering of 20 nm Au Nanoparticles

Collaborator: P. Price, A. Monterrosa, & IDES Inc.

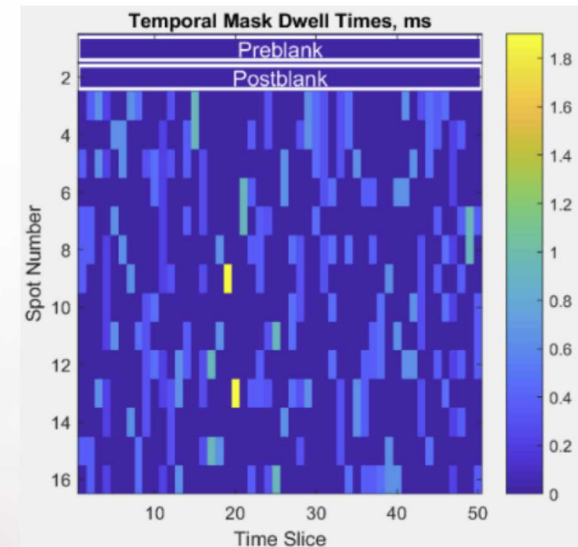
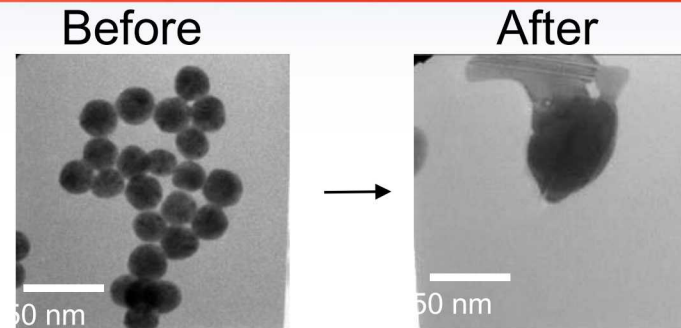
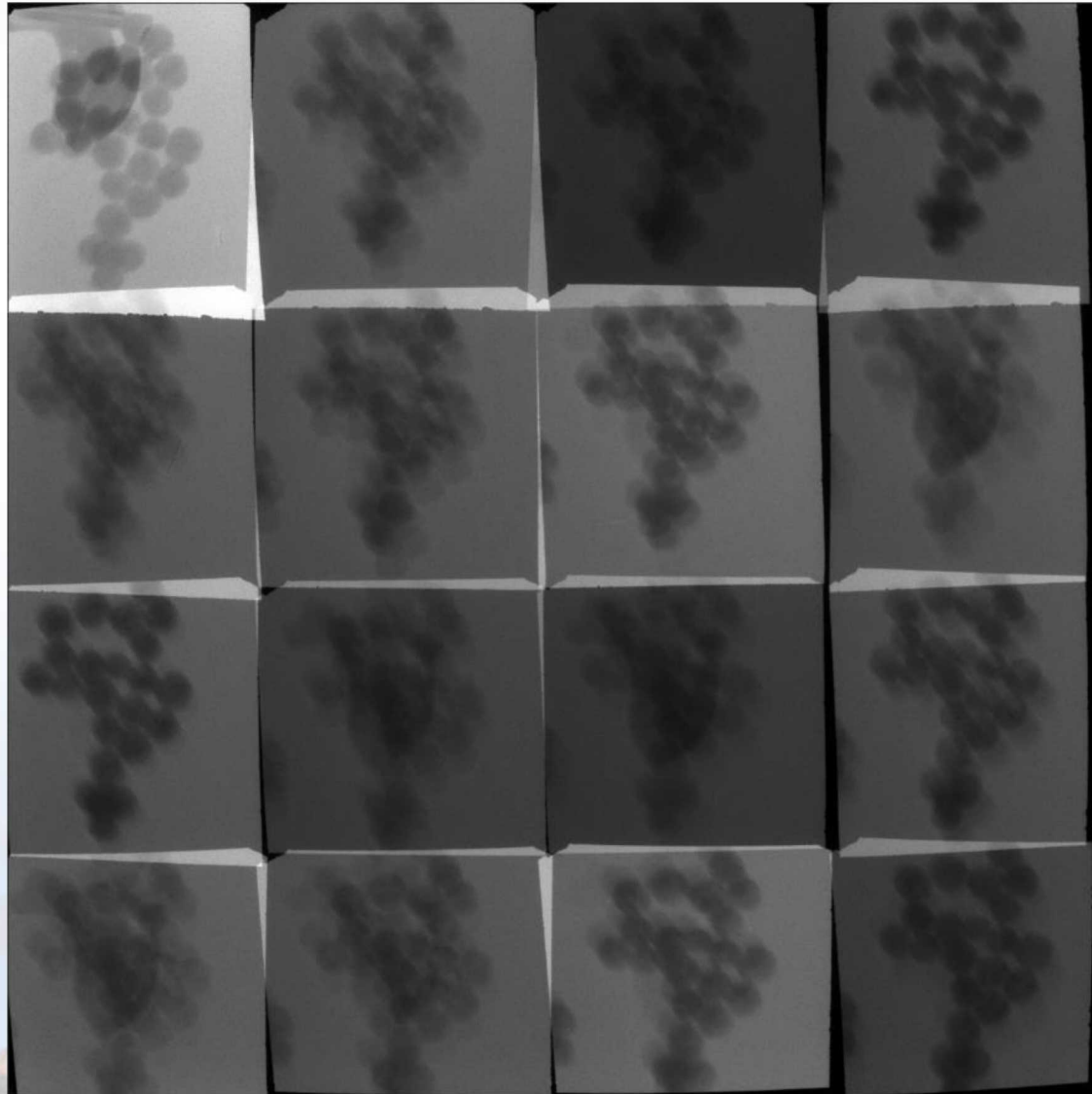


16 frames captured with <5 ms  
exposure per frame



# Temporal Compressive Sensing to Improve Temporal Resolution

Collaborator: P. Price, A. Monterrosa, & IDES Inc.

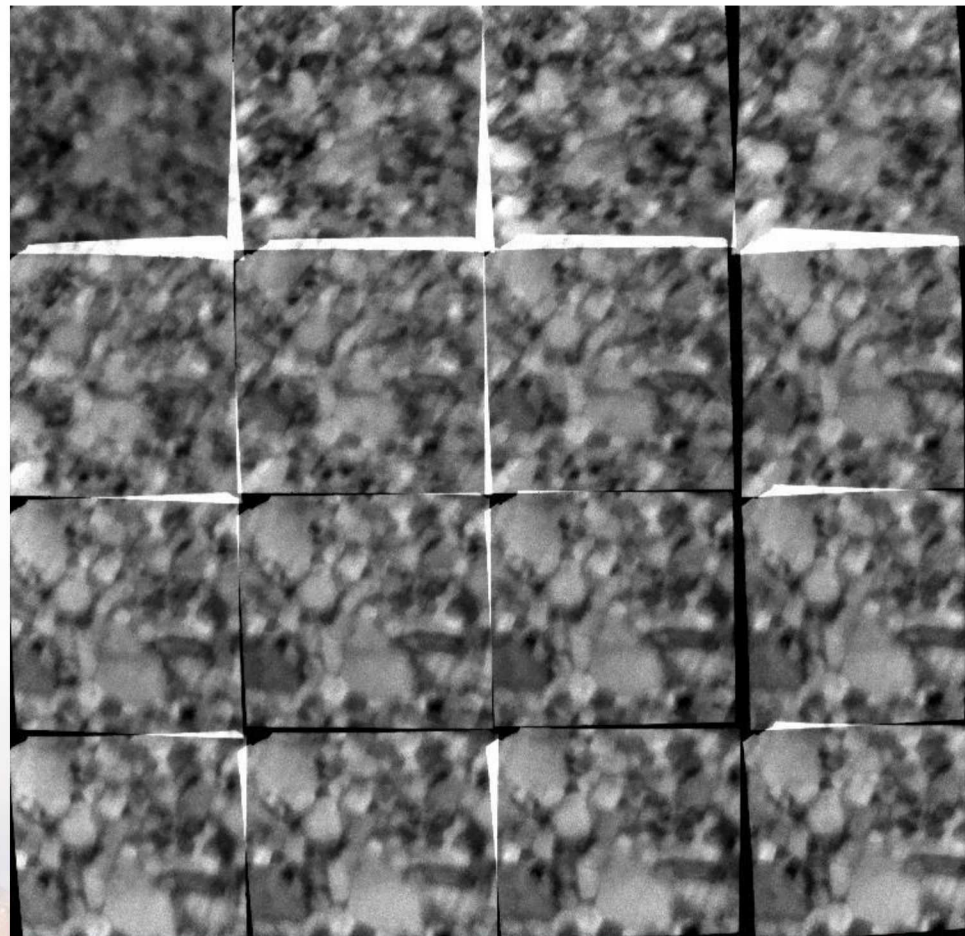
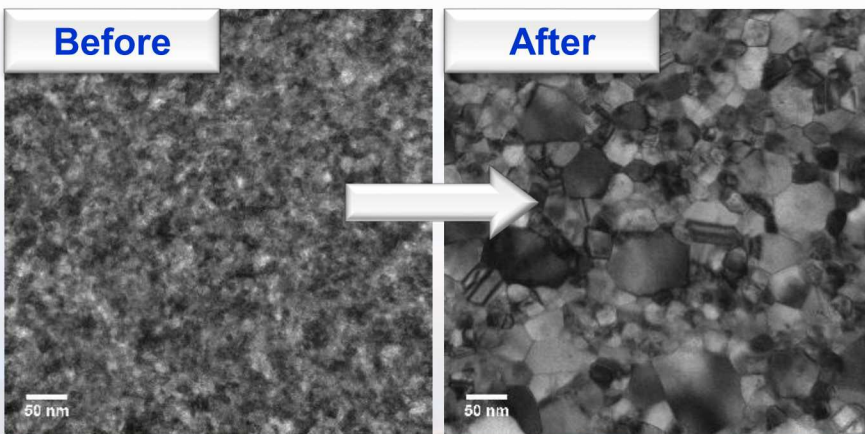


**A pseudorandom exposure pattern can produce more than 16 frames within the same exposure time**

# Motivation: In-situ Microstructure Evolution

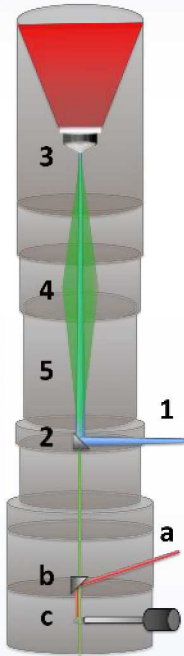
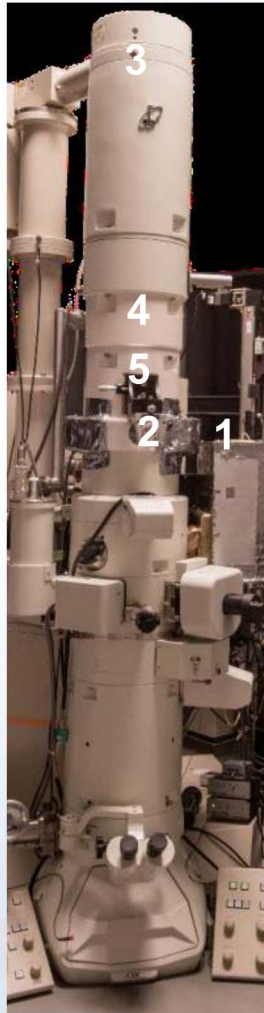
- In-situ TEM images of IR laser driven grain growth in Pt foil
- Characterize grain boundary and grain evolution
- Rapid heating & cooling controlled by specimen drive laser

**Deflector System: Evolution of Pt microstructure with ~10ms exposures shown on the right**





# Conversion of a Standard JEOL 2100 TEM to DTEM: Increase Current Density



**C<sub>0</sub> Lens**



**Drift Section**



**UV Laser**

A standard LaB<sub>6</sub> TEM has on average 1 or 2 electrons in the column at a given time!

Laser induced photoemission of electrons can increase nanosecond electron current by 6-8 orders of magnitude

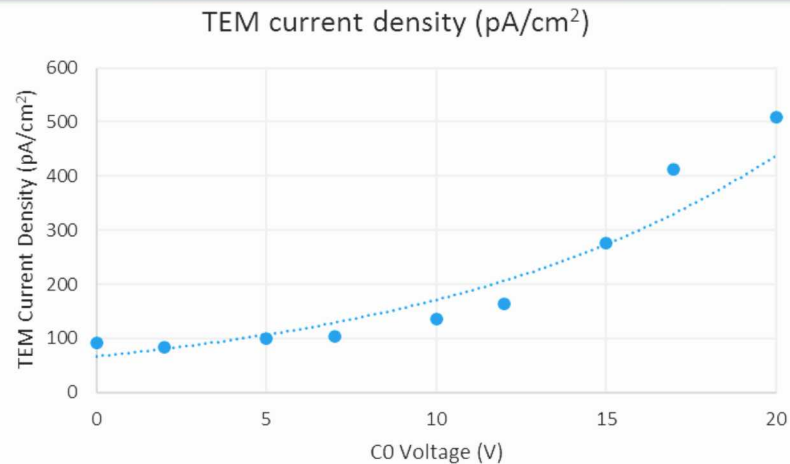
## DTEM Development

1. Ultraviolet laser and optics system capable of producing nanosecond pulses
2. Adjustable molybdenum mirror assembly to reflect the UV laser up the column
3. Tantalum cathode disc filament
4. Addition of a C<sub>0</sub> lens and power supply to gather electrons increasing current to the specimen
5. Addition of a drift section to condense electrons from the C<sub>0</sub> lens
6. Lead shielding as needed to ensure safe operation of the instrument

# Increased Current Density & added 18" to TEM Column



**Addition of  $C_0$  lens and drift section give a 5X increase in current density**



- Disc cathode produces wider distribution of electrons than  $\text{LaB}_6$
- Current density can be increased by adding  $C_0$  lens to condense electrons to a smaller probe
- Strength of  $C_0$  lens is controlled by external adjustable power supply
  - Trade off between current density and resolution
- Drift section gives more time for electrons to condense after the  $C_0$  lens.  $C_0$  can be weaker

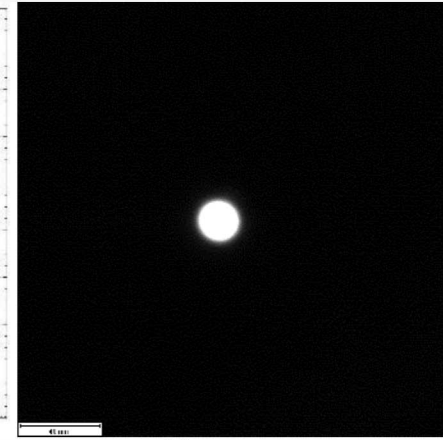
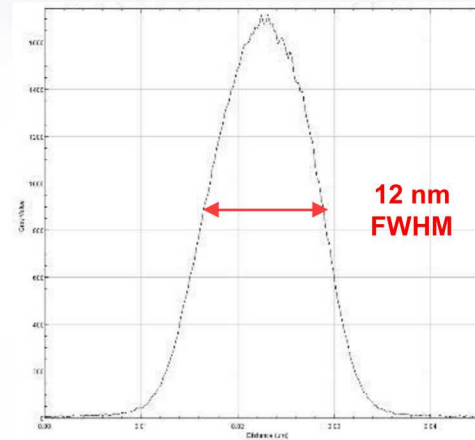




# Tantalum Filament Exchange

## ■ Changes with $C_0$ lens setting of 0V

- 50% reduction in electron
  - ♦  $\text{LaB}_6$  ~ 50 pA/cm<sup>2</sup>
  - ♦ Ta ~ 30 pA/cm<sup>2</sup>
- Higher beam current at from source
  - ♦  $\text{LaB}_6$  ~ 7  $\mu\text{A}$
  - ♦ Ta ~ 23  $\mu\text{A}$
- Increase in minimum spot size for precession
  - ♦  $\text{LaB}_6$  ~ 8 nm FWHM
  - ♦ Ta ~ 12 nm FWHM

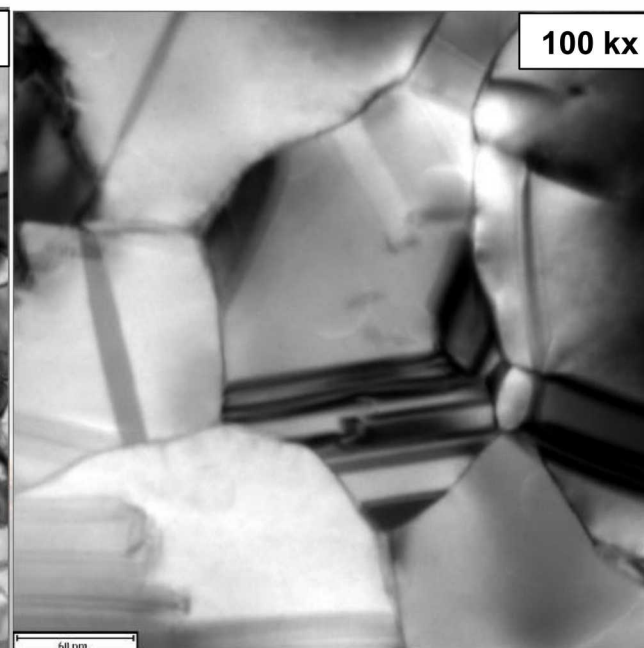
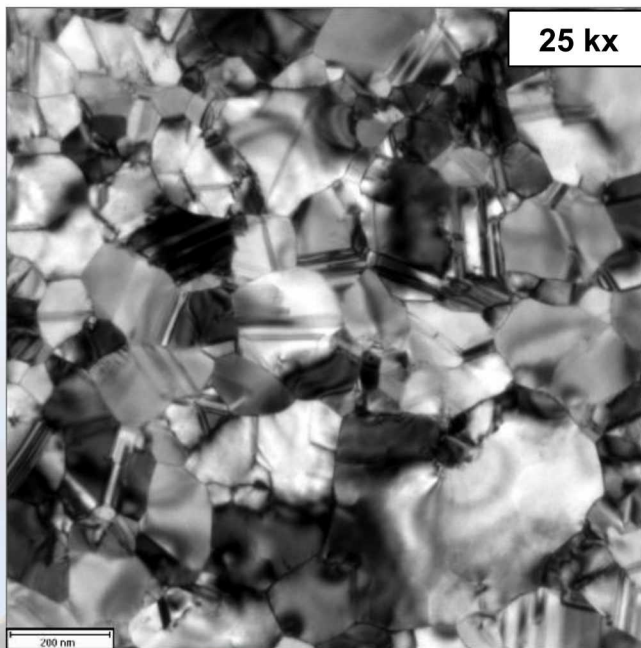


**Above:**

Smallest achievable spot size for precession with Ta cathode

**Left:**

Bright field TEM images of nanocrystalline gold taken with Ta filament



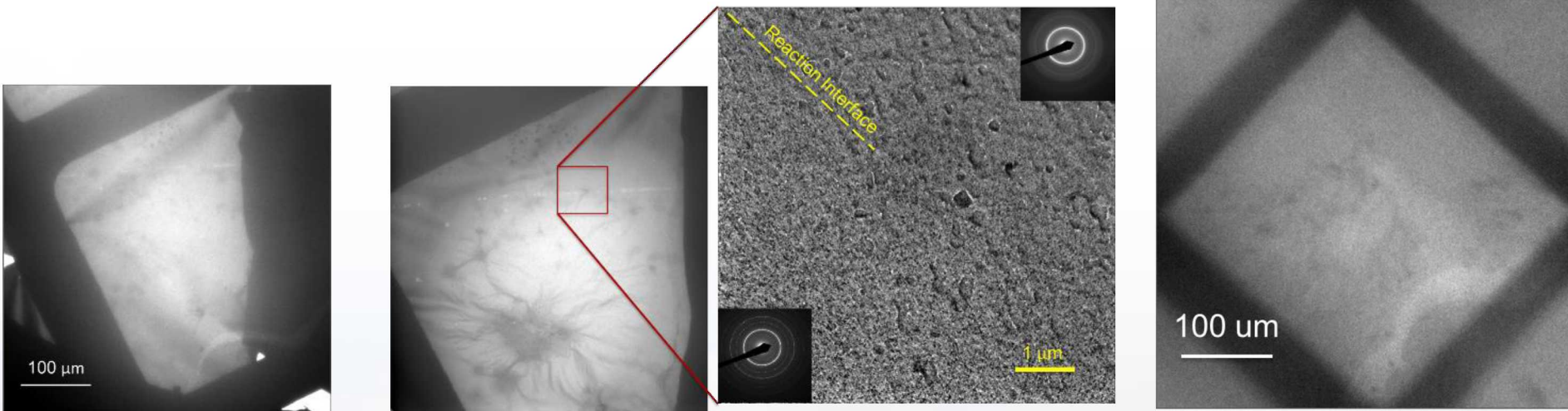
**Easily switch between DTEM and thermal emission with good resolution in minutes!**

**Filament exchange in as little as 90 min.**



# DTEM of Reactive Multilayers

Reactive multilayers provide an excellent example of the capabilities of DTEM. Al/Co multilayer samples are ignited by the IR laser, and convert to a CoAl phase. The reaction front propagates across the sample at  $\sim 10$  m/s. With a fast enough time resolution this wavefront can be captured.



Al/Co  
multilayer  
sample **before**  
IR laser shot

Al/Co multilayer sample **after IR laser shot**  
and closeup of reaction interface

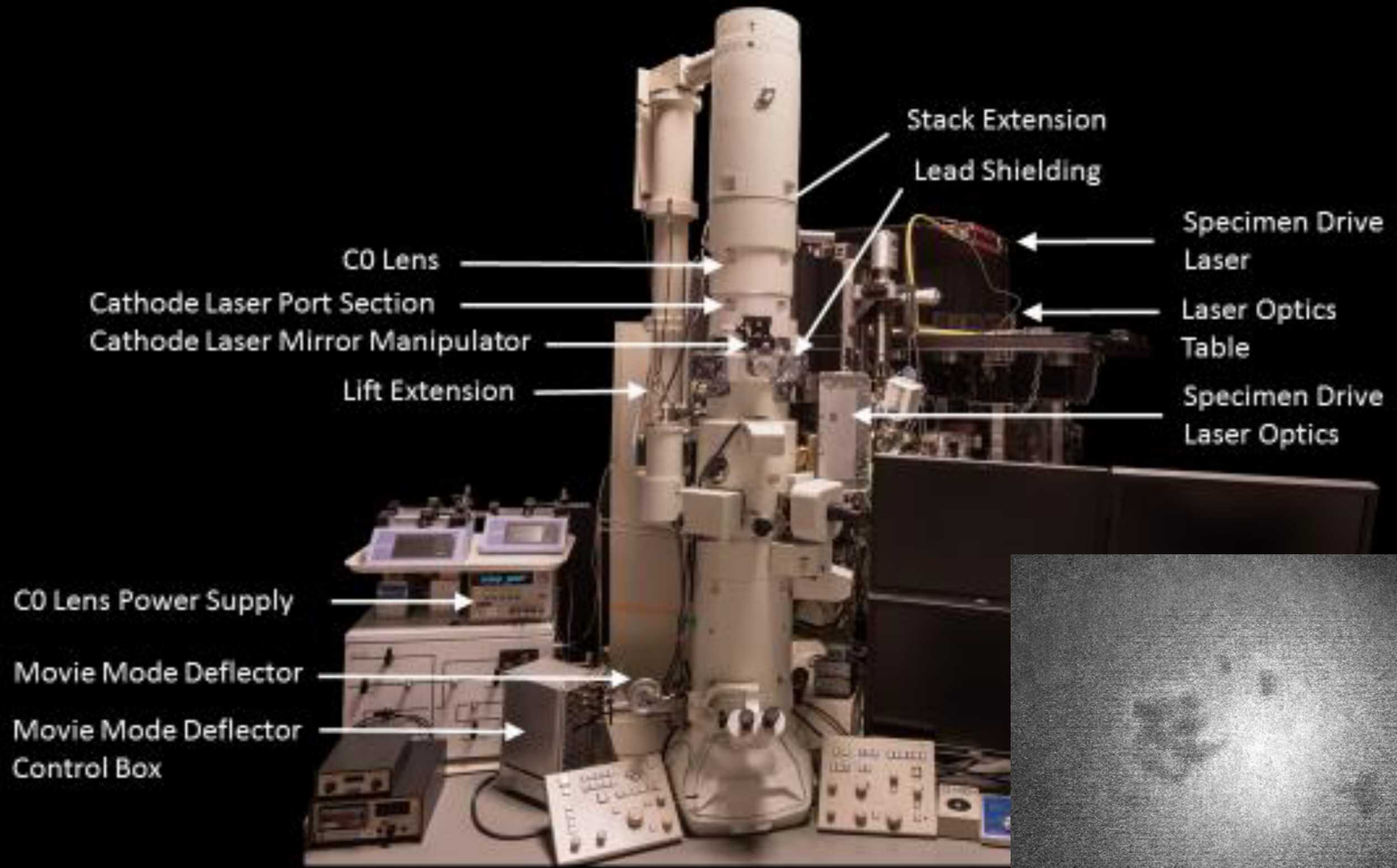
**Single shot DTEM** of  
unreacted Al/Co  
multilayer sample





# Current Status of DTEM Conversion

Collaborator: P. Price, A. Monterrosa, C.M. Barr, D. Adams, M. Abere, & IDES Inc.



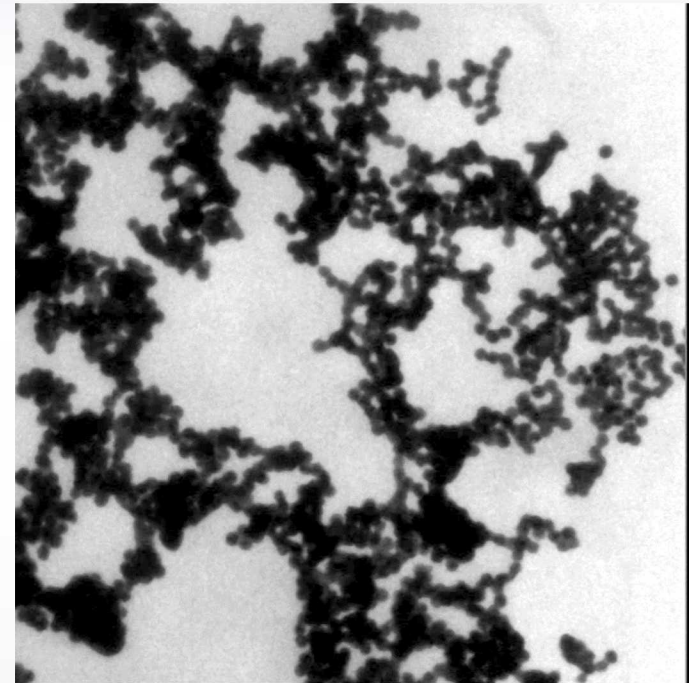
- 266 nm UV laser induced photoemission has been achieved!
- 6 ns single-shot DTEM image of P47



# Unconventional *In situ* Microscopy Creates a wealth of Possibilities

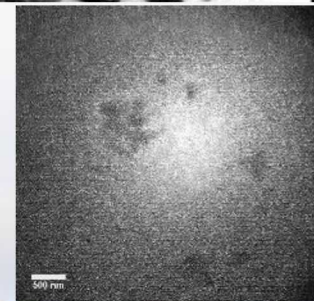
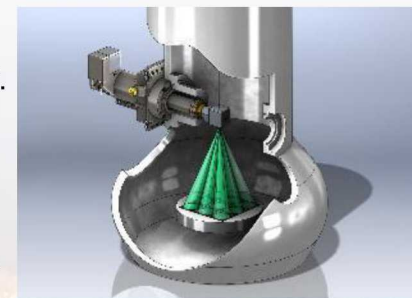


- Fundamental TEM modifications for DTEM, movie mode, and compressive sensing have progressed.
- Maintained functionality of the TEM using LaB<sub>6</sub> thermal emission with minimal impact
- Possible to switch between LaB<sub>6</sub> and DTEM in just a few hours
- Compressive sensing permits microsecond temporal resolution
- Laser induced photoemission of electrons has been achieved with in single shot 6 ns temporal resolution
- Advanced temporal resolution on the I<sup>3</sup>TEM combined with the wide range of available in-situ capacities provide a wealth of experimental control



## Collaborators:

D.L. Buller, D.C. Bufford, S.H. Pratt, T.J. Boyle, B.A. Hernandez-Sanchez, S.J. Blair, B. Muntifering, C. Chisholm, P. Hosemann, A. Minor, J. A. Hinks, F. Hibberd, A. Ilinov, D. C. Bufford, F. Djurabekova, G. Greaves, A. Kuronen, S. E. Donnelly, K. Nordlund, F. Abdeljawad, S.M. Foiles, J. Qu, C. Taylor, J. Sugar, P. Price, C.M. Barr, D. Adams, M. Abernethy, L. Treadwell, A. Cook, A. Monterrosa, IDES Inc, J. Sharon, B. L. Boyce, C. Chisholm, H. Bei, E.P. George, W. Mook, Hysitron Inc., G.S. Jawaharram, S. Dillon, R.S. Averbach, N. Heckman, J. Carroll, S. Briggs, E. Carnes, J. Brinker, D. Sasaki, T. Nenoff, B.G. Clark, P.J. Cappillino, B.W. Jacobs, M.A. Hekmaty, D.B. Robinson, L.R. Parent, I. Arslan. & Protochips



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# Sandia's USER Capabilities



D. Hanson, W. Martin, M. Wasiolek

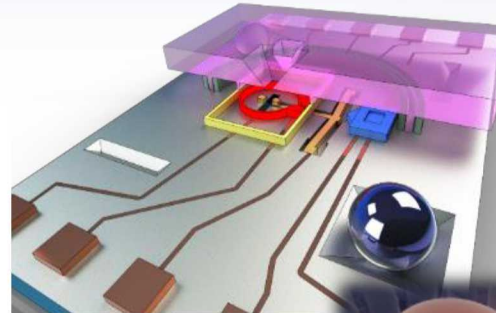
[www.cint.lanl.gov](http://www.cint.lanl.gov)

- Spring and Fall proposals for 18 months
- Rapid Access proposal anytime for 3 months

Core Facility - SNL

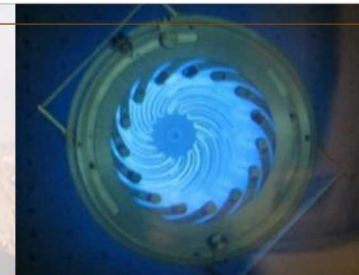
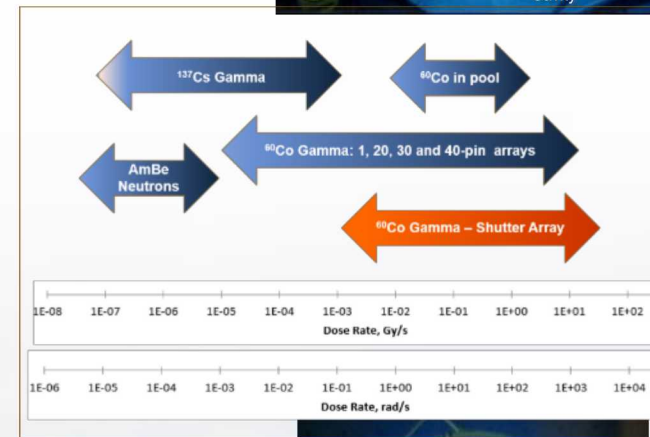
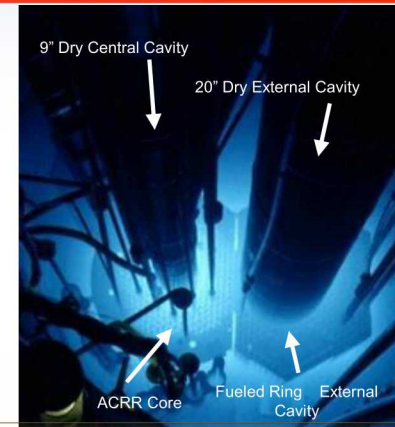


Gateway Facility - LANL



[www.nsunf.inl.gov](http://www.nsunf.inl.gov)

- Three proposal a year for 9 months



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